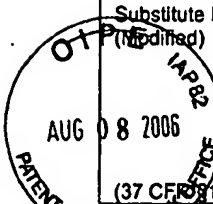


|  |   |  |                                       |                               |
|--|---|--|---------------------------------------|-------------------------------|
|  | Substitute Form PTO-1449<br>(Modified)  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>10559-918001 | Application No.<br>10/799,435 |
|  | <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary) |  | Applicant<br>Alexander Tregub et al.  |                               |
|  |   |  | Filing Date<br>March 12, 2004         | Group Art Unit<br>1773        |

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| Substitute Form PTO-1449<br>(Modified)<br><br><b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br><br>(37 CFR §1.98(b)) | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br><b>10559-918001</b> | Application No.<br><b>10/799,435</b> |
|  | Applicant<br><b>Alexander Tregub et al.</b>                |  |                                      |
|  | Filing Date<br><b>March 12, 2004</b>                       | Group Art Unit<br><b>1773</b>                |                                      |

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|   |           |                 |                  |                          |       |          | Yes         | No   |
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| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br><br>(37 CFR §1.98(b)) |  | Applicant<br>Alexander Tregub et al.  |                               |
|  |  | Filing Date<br>March 12, 2004         | Group-Art Unit<br>1773        |

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| Examiner Signature   | /Ramsey Zacharia/ | Date Considered | 12/06/2006 |
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|                       | AE        |                 |                  |          |       |          |                            |
|                       | AF        |                 |                  |          |       |          |                            |
|                       | AG        |                 |                  |          |       |          |                            |
|                       | AH        |                 |                  |          |       |          |                            |
|                       | AI        |                 |                  |          |       |          |                            |
|                       | AJ        |                 |                  |          |       |          |                            |
|                       | AK        |                 |                  |          |       |          |                            |

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| Examiner Initial  | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|   |           |                 |                  |                          |       |          | Yes         | No |
|   | AL        |                 |                  |                          |       |          |             |    |
|   | AM        |                 |                  |                          |       |          |             |    |
|   | AN        |                 |                  |                          |       |          |             |    |
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